

PURCHASE ORDER ATTACHMENT TQA-42 (00)

LOT ACCEPTANCE TEST (LAT) DATA

1. The Seller shall provide lot acceptance test (LAT) data per NWC 2670 with each shipment. The test data shall contain information such that the test data is traceable to the hardware tested and being presented for acceptance. Appropriate information such as part number, revision letter, Purchase Order number, supplier name, lot number/date code, etc., shall be used.
2. The sample selection for LAT shall be a random sample selected from the chips of a single inspection lot and be in accordance with NWC 2670 and the following: In the case of multiple wafers comprising an inspection lot, the LAT sample must be distributed across all wafers represented in the inspection lot. It is not acceptable to select a single wafer from a multi-wafer inspection lot and draw all the LAT samples from it alone. At least five (5) samples shall be selected from each wafer in the inspection lot. Canned samples shall be serialized for all testing (qualification and LAT) such that it provides traceability from hardware to test data.